<u>AMENDMENTS TO THE SPECIFICATION:</u>

Page 1, amend paragraph [0004] as:

[0004] The dedicated testing chooses points to be tested according to circuit layout of

a tested printed circuit board and chooses proper spring probes according to the size of

the points to be tested and the distance between adjacent points to be tested. Two

principles are employed in choosing the spring probes: (1) whether or not, the spring

probes include features suitable to test the points; (2) after the receptacles of the probes

inserted in the fixing board of test fixture, no short circuit happened. The diameters

diameter of receptacles for the spring probes are within the range between 0.45m/m to

1.65 m/m.

Page 2, amend paragraph [0006] as:

[0006] When using the dedicated tester, the test fixture has to be fixed to the press of

the tester and the connectors on the test fixture are connected to the tester with flat cables

so that each probe is connected to a test node in the tester. When the press is lowered,

the spring in the probe is applied by a force so that the plunger of the probe and the point

to be tested on the printed circuit board [[is]] are electrically connected [[such]] so that

the points to be tested on the printed circuit board become conductive with the test node

in the tester because of close contact. This can be used to test the open/short of each

trace of the layout.

Page 2, amend paragraph [0008] as:

[0008] The present invention relates to a method for testing a printed circuit board

and the method is carried out by using an innovative dedicated test fixture, which

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employs conductive rubber and a dedicated specially shaped printed circuit board. The

test fixture can be easily manufactured and is less expensive. The innovative method of

the present invention allows for easy test of sophisticated printed circuit boards with

small pads arranged in for example 0.1 millimeter width and 0.15 millimeter millimeter

gap.

Page 3, amend paragraph [0016] as:

[0016] The present invention relates to a method for testing printed circuit boards.

The method is carried out by using a dedicated test fixture that is made of conductive

rubber and a dedicated special shaped printed circuit board.

Page 4, amend paragraph [0017] as:

[0017] Referring to Figure 1, step 101 first proceeds, which uses software to choose

points to be tested on the printed circuit board. Step 102 then proceeds, which uses all

information about the points to be tested and manufactures manufacture a testing board

having protrusive metal points. The coordinates of the protrusive metal points on the

testing board and the points to be tested on the printed circuit board are the same. There

are holes for connectors defined in a side of the testing board of fixture for inserting such

that the connectors are inserted to the testing board of fixture.

Page 4, amend paragraph [0018] as:

[0018] Step 103 connects all the protrusive metal points to the holes in a side on the

testing board having protrusive metal points by layouts. Step 104 proceeds is preceded

and the testing board having protrusive metal points is connected to the dedicated tester

through flat cables so that each protrusive metal point is connected to a test node in the

tester.

Page 4, amend paragraph [0019] as:

[0019] After that, In step 105 the is preceded and liquid conductive rubber is coated

to the tip of each protrusive metal point. After the liquid conductive rubber is solidified,

a knife is used to trim them to make all the conductive rubbers are in flush with each

other. Step 106 aligns is then preceded to align the points to be tested on the printed

circuit board with the protrusive metal points on the testing board. Then step 107

proceeds is preceded to connect the protrusive metal points with the points to be tested on

the printed circuit board by using the pressure from the press and the flexibility of the

conductive rubber.

Page 4, amend paragraph [0020] as:

[0020] Because the conductive rubber is flexible, so that it compensates for the

differences of height between the points to be tested on the printed circuit board and

allows the testing board having protrusive metal points to contact the points to be tested

on the printed circuit board in good condition. The result for testing open/short of each

trace of layout on the printed circuit board is excellent. If the protrusive metal points are

higher than the connection circuits on the testing board, the contact between the

protrusive metal points and the points to be tested on the printed circuit board will be

much better.

Pages 4-5, amend paragraph [0021] as:

[0021] Figure 2 is a flow chart of a second embodiment of the present invention. In

Figure 2, step 101 first proceeds, which uses software to choose points to be tested on the

printed print circuit board. Step 102 then proceeds, which uses all information about the

points to be tested and manufactures manufacture a testing board having protrusive metal

points. The coordinates of the protrusive metal points on testing board and the points to

be tested on the printed print circuit board are the same. The protrusive metal points are

higher than the rest of the layout. There are holes for connectors defined in a side of the

testing board for inserting such that the connectors are inserted to the testing board.

Page 5, amend paragraph [0022] as:

[0022] Step 103 is preceded, which connects all the protruding metal points to the

holes in a side of the testing board having protrusive metal points by layouts. Step 104

proceeds is preceded and the testing board having protrusive metal points is connected to

the dedicated tester through flat cables so that each protrusive metal point is connected to

a test node in the tester. The protrusive metal points are higher than the rest of the layout.

Page 5, amend paragraph [0023] as:

[0023] Then step 205 proceeds to insert is preceded, inserted a pressure sensitive

conductive rubber layer between the testing board having protrusive metal points and the

printed circuit board to be tested. Step 206 proceeds is preceded and the press of the

tester applies a pressure to the protrusive metal points and the points to be tested on the

printed circuit board so that the pressure sensitive conductive rubber senses the pressure

layer, which electrically connects the protrusive metal points and the points on the

printed circuit board. The open/short of each trace on the printed circuit board can be

tested.

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Page 5, amend paragraph [0024] as:

[0024] Figure 3 is a flow chart of a third embodiment of the present invention. In

Figure 3, step 101 first proceeds, which uses software to choose points to be tested on the

printed circuit board. Step 102 then proceeds, which uses all information about the

points to be tested and manufactures manufacture a testing board having protrusive metal

points. The coordinates of the metal points and the points to be tested on the printed

circuit board are the same. There are holes for connectors defined in a side of the testing

board for inserting such that the connectors are inserted to the testing board. The number

of the holes has to be larger than or equal to the sum of the protrusive metal points.

Page 5, amend paragraph [0025] as:

[0025] Step 103 connects all the protrusive metal points to the holes in a side of the

testing board having protrusive metal points by layouts. Step 104 proceeds and the

testing board having protrusive metal points is connected to the dedicated tester through

flat cables so that each protrusive metal point is connected to a test node in the tester.

The protrusive metal points are higher than the rest of the layout.

Page 5, amend paragraph [0026] as:

[0026] Finally, step 305 proceeds, and each protrusive metal point is taped with an

electrically z-axis conductive adhesive film which is conductive in vertical direction.

Step 306 then proceeds to align all the points to be tested on the printed print circuit

board and the protrusive metal points on the testing board. Step 307 employs the

pressure of the press of the tester and the flexibility of the conductive adhesive film